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FS2312D

N-mos With Gate Protect Diode

● Features

- 20V/6.5A, RDS(ON)=20 mΩ @VGS=4.5V
- 20V/5.5A, RDS(ON)=23 mΩ @VGS=2.5V
- 20V/5A, RDS(ON)=30 mΩ @VGS=1.8V
- Super high density cell design for extremely low RDS(ON)
- Exceptional on-resistance and maximum DC current Capability

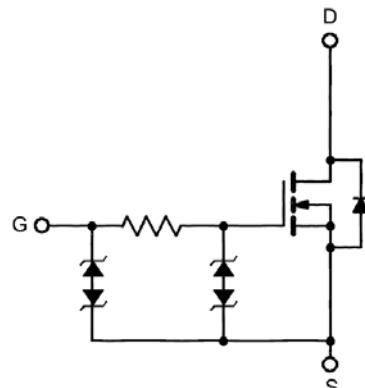
● APPLICATIONS

- Power Management in Note book
- Portable Equipment
- DC/DC Converter
- Load Switch
- DSC
- LCD Display inverter

● General Description

The FS2312D is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching and low in-line power loss are needed in a very small outline surface mount package.

● Pin Configurations



● Absolute Maximum Ratings @ $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDSS	20	V
Gate-Source Voltage	VGSS	±8	V
Continuous Drain Current($tJ=150^\circ\text{C}$)	ID	6.5	A
		5.2	
Pulsed Drain Current	IDM	30	A
Continuous Source Current (Diode Conduction)	IS	2.5	A
Maximum Power Dissipation	PD	1.4	W
		0.9	
Operating Junction Temperature	TJ	-55 to 150	°C
Storage Temperature Range	Tstg	-55 to 150	°C
Thermal Resistance-Junction to Ambient	R _{θJA}	125	°C/W



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- Electrical Characteristics @ $T_A=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Limit	Min	Typ	Max	Unit	
Static							
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250 μA	20			V	
V _{GS(th)}	Gate Threshold Voltage	V _D =V _{GS} , I _D =250 μA	0.4	0.6	1	V	
IGSS	Gate Leakage Current	V _D =0V, V _{GS} = $\pm 4.5\text{V}$			± 1	nA	
		V _D =0V, V _{GS} = $\pm 8\text{V}$			± 10		
IDSS	Zero Gate Voltage Drain Current	V _D =24V, V _{GS} =0V			1	μA	
		V _D =16V, V _{GS} =0V TJ=55°C			1		
ID(ON)	On-State Drain Current	V _D =4.5V, V _{GS} = 5V	30			A	
RDS(ON)	Drain-Source On-Resistance	V _{GS} =4.5V, ID= 6.5A		16	20	$\text{m}\Omega$	
		V _{GS} =2.5V, ID= 5.5A		20	23		
		V _{GS} =1.8V, ID= 5A		25	30		
GFS	Forward Transconductance	V _D =5V, ID=6.5A		13		S	
VSD	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.6	1	V	
Dynamic							
Qg	Total Gate Charge	V _D =10V, V _{GS} =4.5V, I _D =6.5A		10		nC	
Qgs	Gate-Source Charge			1.4			
Qgd	Gate-Drain Charge			2.7			
C _{iss}	Input Capacitance	V _D =10V, V _{GS} =0V, f=1MHz		1100		pF	
C _{oss}	Output Capacitance			104			
C _{rss}	Reverse Transfer Capacitance			29			
R _g	Gate resistance	V _D =10V, V _{GS} =0V, f=1MH		1.5		Ω	
td(on)	Turn-On Time	V _D =10V, RL= 1.5 Ω V _{GS} =5V, R _{GEN} =3 Ω		6.2		ns	
tr				12.7			
td(off)	Turn-Off Time			51.7			
tf				16			

Notes:

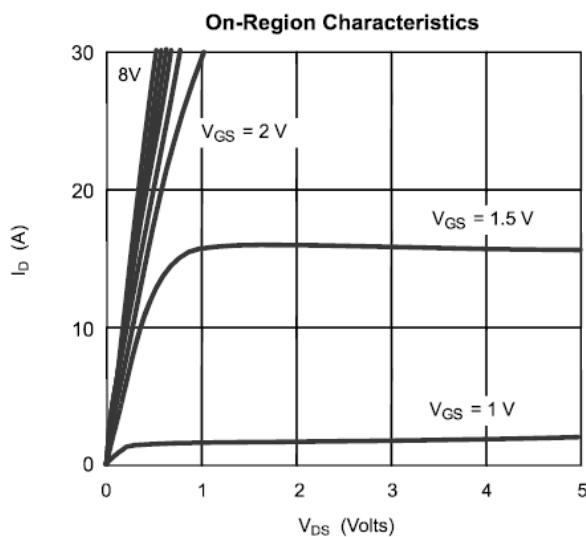
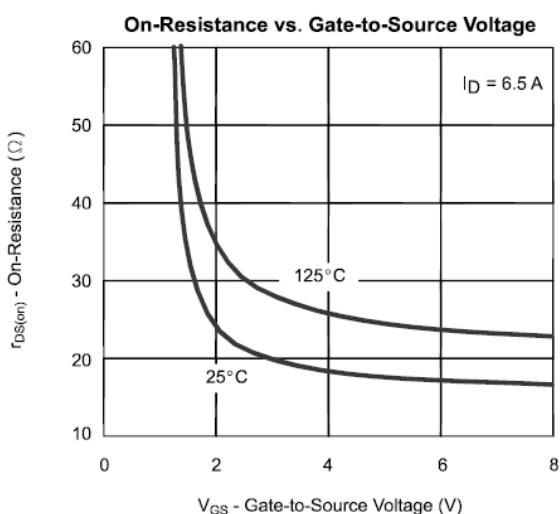
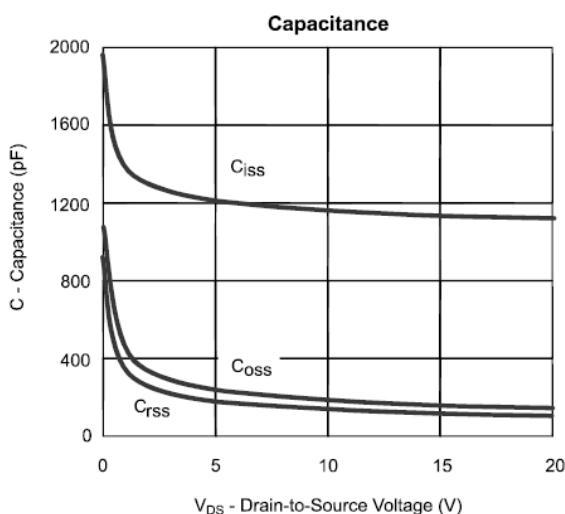
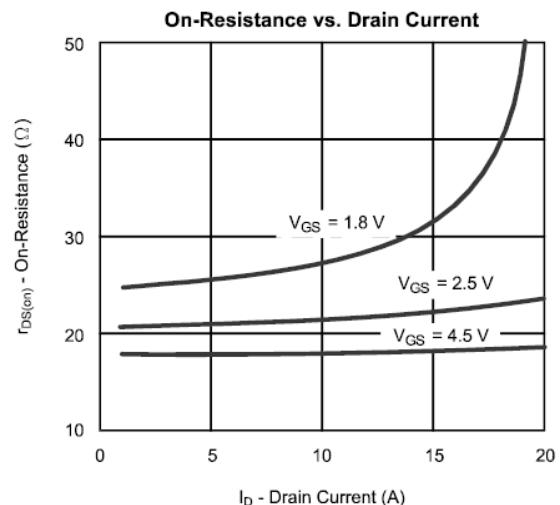
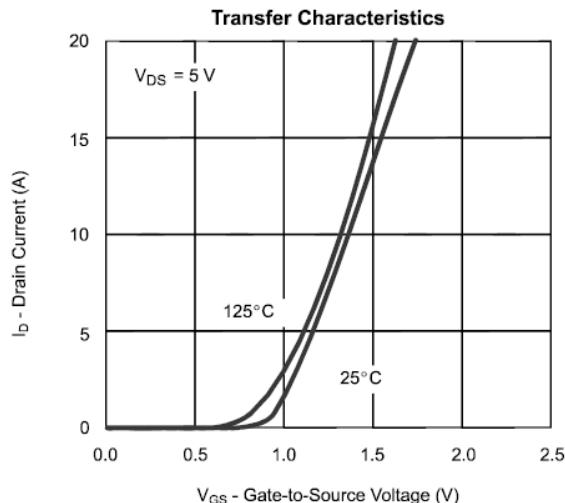
1. Pulse width limited by maximum junction temperature. Pulse test: PW $\leqslant 300\ \mu\text{s}$, duty cycle $\leqslant 2\%$.
2. For design AID only, not subject to production testing. Switching time is essentially independent of operating temperature.



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- Typical Performance Characteristics



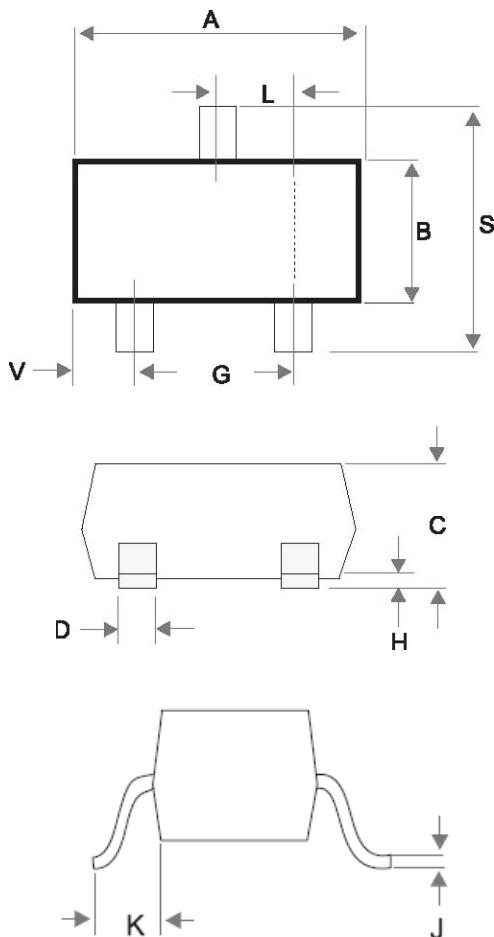


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- Package Information

SOT-23 Package Outline



DIM	MILLIMETERS	
	MIN	MAX
A	2.80	3.1
B	1.20	1.7
C	0.89	1.3
D	0.37	0.50
G	1.78	2.04
H	0.013	0.15
J	0.085	0.2
K	0.45	0.7
L	0.89	1.02
S	2.10	3
V	0.45	0.60